

Notice of References Cited	Application/Control No. 10/594,065		Applicant(s)/Patent Under Reexamination TAKEUCHI ET AL.	
	Examiner VERNON P. WEBB		Art Unit 2811	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0169184 A1	09-2004	Udagawa et al.	257/086
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NON-PATENT DOCUMENTS

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